









TSV911A-Q1, TSV912A-Q1, TSV914A-Q1 SBOSA18C - MAY 2020 - REVISED JUNE 2023

TSV91xA-Q1 Automotive Rail-to-Rail Input or Output, 8-MHz Operational Amplifiers

1 Features

Rail-to-rail input and output

Low noise: 18 nV/√Hz at 1 kHz

Low power consumption: 550 µA (typical)

High-gain bandwidth: 8 MHz

Operating supply voltage from 2.5 V to 5.5 V

Low input bias current: 1 pA (typical)

Low input offset voltage: 1.5 mV (maximum)

Low offset voltage drift: ±0.5 µV/°C (typical)

ESD internal protection: ±4-kV human-body model

Extended temperature range: -40°C to 125°C

2 Applications

- Optimized for AEC-Q100 grade 1 applications
- Infotainment and cluster
- Passive safety
- Body electronics and lighting
- HEV/EV inverter and motor control
- On-board (OBC) and wireless charger
- Powertrain current sensor
- Advanced driver assistance systems (ADAS)
- Single-supply, low-side, unidirectional currentsensing circuit

5 V 0 165 kO **Low-Side Motor Control**

3 Description

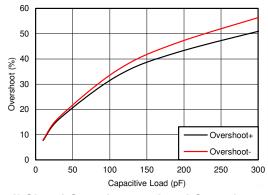
The TSV91xA-Q1 family, which includes single-, dual-, and quad-channel operational amplifiers (op amps), is specifically designed for general-purpose automotive applications. Featuring rail-to-rail input and output (RRIO) swings, wide bandwidth (8 MHz), and low offset voltage (0.3 mV, typical), this family is designed for a variety of applications that require a good balance between speed and power consumption. The op amps are unity-gain stable and feature an ultra-low input bias current, which enables the family to be used in applications with high-source impedance. The low input bias current allows the devices to be used for sensor interfaces, and active filterina.

The robust design of the TSV91xA-Q1 provides easeof-use to the circuit designer. Features include a unity-gain stable, integrated RFI-EMI rejection filter, no phase reversal in overdrive condition, and high electrostatic discharge (ESD) protection (4-kV HBM).

Device Information

PART NUMBER ⁽¹⁾ CHANNEL COUNT ⁽²⁾		PACKAGE ⁽¹⁾	PACKAGE SIZE(3)			
TSV911A-Q1	Single	DBV (SOT-23, 5)	2.90 mm × 2.80 mm			
13v911A-Q1	Single	DCK (SC70, 5)	2.0 mm × 2.20 mm			
		D (SOIC, 8)	4.90 mm × 6.00 mm			
TSV912A-Q1	Dual	DGK (VSSOP, 8)	3.00 mm × 4.90 mm			
		PW (TSSOP, 8)	3.00 mm × 6.40 mm			
TSV914A-Q1	Quad	D (SOIC, 14)	8.65 mm × 6.00 mm			
15V914A-Q1	Quad	PW (TSSOP, 14)	5.00 mm × 6.40 mm			

- For all available packages, see the orderable addendum at the end of the data sheet.
- See the Device Comparison table
- The package size (length × width) is a nominal value and includes pins, where applicable.



Small-Signal Overshoot vs Load Capacitance



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8.1 Overview		

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

nanges from Revision B (February 2021) to Revision C (June 2023)	ge
Added the SC70 package and 8-pin TSSOP package in Device Information table	.1
Removed the preview tag for the SOT-23 package in <i>Device Information</i> table	
Updated the format of the Device Information to include package leads and channel count	
Updated the Device Comparison table to include newer packages	
Added pinout drawings for TSV911A-Q1 in the Pin Configurations and Functions section	
Added the Thermal Information: TSV911A-Q1 section	
Changed input offset voltage at room temperature from ±1.5 mV to ±1.85 mV in <i>Electrical Characteristics</i> Deleted the <i>Packages With an Exposed Thermal Pad</i> section	. 9
nanges from Revision A (December 2020) to Revision B (February 2021) Pag	_ ge
Deleted preview tag from VSSOP package in <i>Device Information</i> table	
nanges from Revision * (June 2020) to Revision A (December 2020)	 ge
Updated the numbering format for tables, figures, and cross-references throughout the document	. 1
Deleted preview tag from TSSOP package in <i>Device Information</i> table	
· · · · · · · · · · · · · · · · · · ·	
Deleted Package, preview note from TSV914-Q1 pinout drawing and <i>Pin Functions</i> table	
Deleted Package, preview note from TSV914-Q1 pinout drawing and <i>Pin Functions</i> table	.4



5 Device Comparison Table

DEVICE	NO. OF	PACKAGE LEADS					
	CHANNELS	DCK	DBV	D	DGK	PW	
TSV911A-Q1	1	5	5	_	_	_	
TSV912A-Q1	2	_	_	8	8	8	
TSV914A-Q1	4	_	_	14	_	14	



6 Pin Configuration and Functions

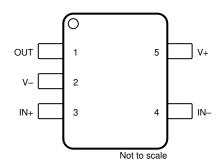


Figure 6-1. TSV911A-Q1 DBV Package, 5-Pin SOT-23 (Top View)

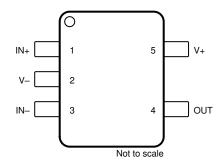


Figure 6-2. TSV911A-Q1 DCK Package, 5-Pin SC70 (Top View)

Table 6-1. Pin Functions: TSV911A-Q1

	PIN		TYPE(1)	DESCRIPTION	
NAME	SOT-23	SC70	1166		
IN-	4	3	I	Inverting input	
IN+	3	1	I	Noninverting input	
OUT	1	4	0	Output	
V-	2	2	l or —	Negative (low) supply or ground (for single-supply operation)	
V+	5	5	I	Positive (high) supply	

(1) I = input, O = output



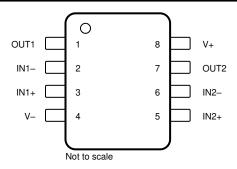


Figure 6-3. TSV912A-Q1 D, PW and DGK Packages, 8-Pin SOIC, TSSOP and VSSOP (Top View)

Table 6-2. Pin Functions: TSV912A-Q1

	PIN	TYPE(1)	DESCRIPTION	
NAME	NO.	TIPE	DESCRIPTION	
–IN A	2	I	Inverting input, channel A	
+IN A	3	I	Noninverting input, channel A	
–IN B	6	I	Inverting input, channel B	
+IN B	5	I	Noninverting input, channel B	
OUT A	1	0	Output, channel A	
OUT B	7	0	Output, channel B	
V-	4	_	Negative (lowest) supply or ground (for single-supply operation)	
V+	8	_	Positive (highest) supply	

(1) I = input, O = output



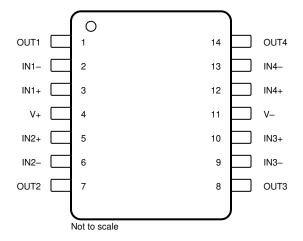


Figure 6-4. TSV914A-Q1 D and PW Packages, 14-Pin SOIC and TSSOP (Top View)

Table 6-3. Pin Functions: TSV914A-Q1

	PIN					
	PIN	TYPE(1)	DESCRIPTION			
NAME	NO.		BESSKII HON			
–IN A	2	I	Inverting input, channel A			
+IN A	3	I	Noninverting input, channel A			
–IN B	6	I	nverting input, channel B			
+IN B	5	I	Noninverting input, channel B			
–IN C	9	I	nverting input, channel C			
+IN C	10	ı	Noninverting input, channel C			
–IN D	13	ı	Inverting input, channel D			
+IN D	12	I	Noninverting input, channel D			
OUT A	1	0	Output, channel A			
OUT B	7	0	Output, channel B			
OUT C	8	0	Output, channel C			
OUT D	14	0	Output, channel D			
V-	11	_	Negative (lowest) supply or ground (for single-supply operation)			
V+	4	_	Positive (highest) supply			

(1) I = input, O = output



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature (unless otherwise noted)(1)

		· · · · · · · · · · · · · · · · · · ·	MIN	MAX	UNIT	
Supply voltage				6	V	
	Voltage ⁽²⁾	Common-mode	(V-) - 0.	5 (V+) + 0.5	V	
Signal input pins	voltage	Differential ⁽⁴⁾		(V+) - (V-) + 0.2	V	
	Current ⁽²⁾		-10	10	mA	
Output short-circuit	(3)			Continuous	mA	
Specified, T _A			-40	125	°C	
Junction, T _J				150	°C	
Storage, T _{stg}			-65	150	°C	

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Input pins are diode-clamped to the power-supply rails. Current limit input signals that can swing more than 0.5 V beyond the supply rails to 10 mA or less.
- (3) Short-circuit to ground, one amplifier per package.
- (4) Differential input voltages greater than 0.5 V applied continuously can result in a shift to the input offset voltage above the maximum specification of this parameter. The magnitude of this effect increases as the ambient operating temperature rises.

7.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±4000	\ \ \ \ \ \
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±1500	V

⁽¹⁾ AEC Q100-002 indicates that HBM stressing shall be in accordance with ANSI/ESDA/JEDEC JS-001 Specification.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
Vs	Supply voltage	2.5	5.5	V
	Specified temperature	-40	125	°C



7.4 Thermal Information: TSV911A-Q1

		TSV91		
THERMAL METRIC(1)		DBV (SOT-23)	DCK (SC70)	UNIT
		5 PINS	5 PINS	
R _{0JA}	Junction-to-ambient thermal resistance	232.5	246.6	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	131.0	157.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	99.6	95.4	°C/W
ΨЈТ	Junction-to-top characterization parameter	66.5	68.8	°C/W
ΨЈВ	Junction-to-board characterization parameter	99.1	95.0	°C/W

7.5 Thermal Information: TSV912A-Q1

			TSV912A-Q1			
	THERMAL METRIC ⁽¹⁾	D (SOIC)	PW (TSSOP)	DGK (VSSOP)	UNIT	
		8 PINS	8 PINS	8 PINS		
R _{θJA}	Junction-to-ambient thermal resistance	157.6	205.1	198.5	°C/W	
R ₀ JC(top)	Junction-to-case (top) thermal resistance	104.6	93.7	87.2	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	99.7	135.7	120.3	°C/W	
Ψ_{JT}	Junction-to-top characterization parameter	55.6	25.0	23.8	°C/W	
ΨЈВ	Junction-to-board characterization parameter	99.2	134.0	118.7	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

7.6 Thermal Information: TSV914A-Q1

		TSV91		
	THERMAL METRIC(1)	D (SOIC)	PW (TSSOP)	UNIT
		14 PINS	14 PINS	
R _{0JA}	Junction-to-ambient thermal resistance	111.1	133.8	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	67.6	62.1	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	67	76.9	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	27.4	13.2	°C/W
ΨЈВ	Junction-to-board characterization parameter	66.6	76.3	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



7.7 Electrical Characteristics

 V_S (Total Supply Voltage) = (V+) – (V–) = 2.5 V to 5.5 V at T_A = 25°C, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFFSET	VOLTAGE						
		V _S = 5 V		±0.3	±1.85		
Vos	Input offset voltage	V _S = 5 V T _A = -40°C to 125°C			±3	mV	
dV _{OS} /dT	Drift	V _S = 5 V T _A = -40°C to 125°C		±0.5		μV/°C	
PSRR	Power-supply rejection ratio	V _S = 2.5 V – 5.5 V, V _{CM} = (V–)		±7		μV/V	
	Channel separation, DC	At DC		100		dB	
INPUT V	OLTAGE RANGE		<u> </u>				
V _{CM}	Common-mode voltage range	V _S = 2.5 V to 5.5 V	(V-) - 0.1		(V+) + 0.1	V	
		$V_S = 5.5 \text{ V}$ $(V-) - 0.1 \text{ V} < V_{CM} < (V+) - 1.4 \text{ V}$ $T_A = -40^{\circ}\text{C}$ to 125°C	80	103			
CMRR	Common-mode rejection ratio	$V_S = 5.5 \text{ V}, V_{CM} = -0.1 \text{ V to } 5.6 \text{ V}$ $T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	57	75		dB	
		$V_S = 2.5 \text{ V}, (V-) - 0.1 \text{ V} < V_{CM} < (V+) - 1.4 \text{ V}$ $T_A = -40 ^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$		88			
		$V_S = 2.5 \text{ V}, V_{CM} = -0.1 \text{ V to } 1.9 \text{ V}$ $T_A = -40 ^{\circ}\text{C} \text{ to } 125 ^{\circ}\text{C}$		70	70		
INPUT B	SIAS CURRENT						
I _B	Input bias current			±5		pA	
Ios	Input offset current			±5		pA	
NOISE					'		
En	Input voltage noise (peak-to-peak)	V _S = 5 V, f = 0.1 Hz to 10 Hz		4.77		μV _{PP}	
		V _S = 5 V, f = 10 kHz		12			
e _n	Input voltage noise density	V _S = 5 V, f = 1 kHz		18		nV/√ H	
i _n	Input current noise density	f = 1 kHz		23		fA/√ H	
	APACITANCE						
C _{ID}	Differential			2		pF	
C _{IC}	Common-mode			4		pF	
	OOP GAIN					•	
		$V_S = 2.5 \text{ V}, (V-) + 0.04 \text{ V} < V_O < (V+) - 0.04 \text{ V}$ $R_L = 10 \text{ k}\Omega$		100			
		$V_S = 5.5 \text{ V}, (V-) + 0.05 \text{ V} < V_O < (V+) - 0.05 \text{ V}$ $R_L = 10 \text{ k}\Omega$	104	130		15	
A _{OL}	Open-loop voltage gain	$V_S = 2.5 \text{ V}, (V-) + 0.06 \text{ V} < V_O < (V+) - 0.06 \text{ V}$ $R_L = 2 \text{ k}\Omega$			dB		
		$V_S = 5.5 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V}$ $R_L = 2 \text{ k}\Omega$		130			
FREQUE	ENCY RESPONSE						
GBP	Gain bandwidth product	V _S = 5 V, G = 1		8		MHz	
φ _m	Phase margin	V _S = 5 V, G = 1		55		0	
SR	Slew rate	$V_S = 5 \text{ V, } G = 1$ $R_L = 2 \text{ k}\Omega$ $C_L = 100 \text{ pF}$		4.5		V/µs	
to	Settling time	To 0.1%, $V_S = 5$ V, 2-V step , $G = 1$ $C_L = 100$ pF		0.5		μs	
t _S Settling time		To 0.01%, $V_S = 5$ V, 2-V step , $G = 1$ $C_L = 100$ pF		1		μ5	
t _{OR}	Overload recovery time	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} > V_S$		0.2		μs	
THD + N	Total harmonic distortion + noise ⁽¹⁾	V _S = 5 V, V _O = 1 V _{RMS} , G = 1, f = 1 kHz		0.0008%			



7.7 Electrical Characteristics (continued)

 V_S (Total Supply Voltage) = (V+) – (V–) = 2.5 V to 5.5 V at T_A = 25°C, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)

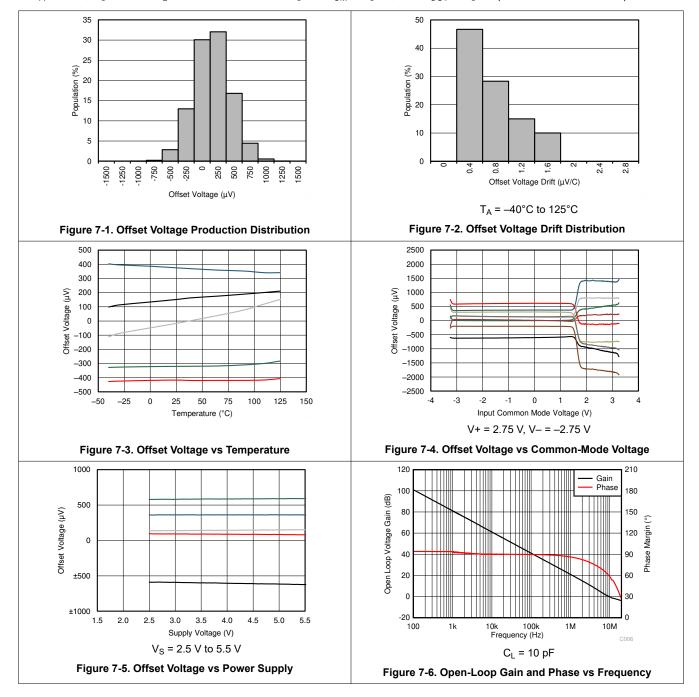
*001	75 / 2 (dillect of lotter little little						
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OUTP	υτ						
V	Voltage output swing from supply	$V_S = 5.5 \text{ V}, R_L = 10 \text{ k}Ω$			20	mV	
Vo	o rails	$V_{S} = 5.5 \text{ V}, R_{L} = 2 \text{ k}\Omega$		60			
I _{SC}	Short-circuit current	V _S = 5 V		±50		mA	
Z _O	Open-loop output impedance	V _S = 5 V, f = 10 MHz		100		Ω	
POWER SUPPLY							
IQ	Quiescent current per amplifier	$V_S = 5.5 \text{ V}, I_O = 0 \text{ mA}$ 550		750			
	Quiescent current per amplifier	$V_S = 5.5 \text{ V}, I_O = 0 \text{ mA } T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$			1100	μA	

⁽¹⁾ Third-order filter; bandwidth = 80 kHz at -3 dB.



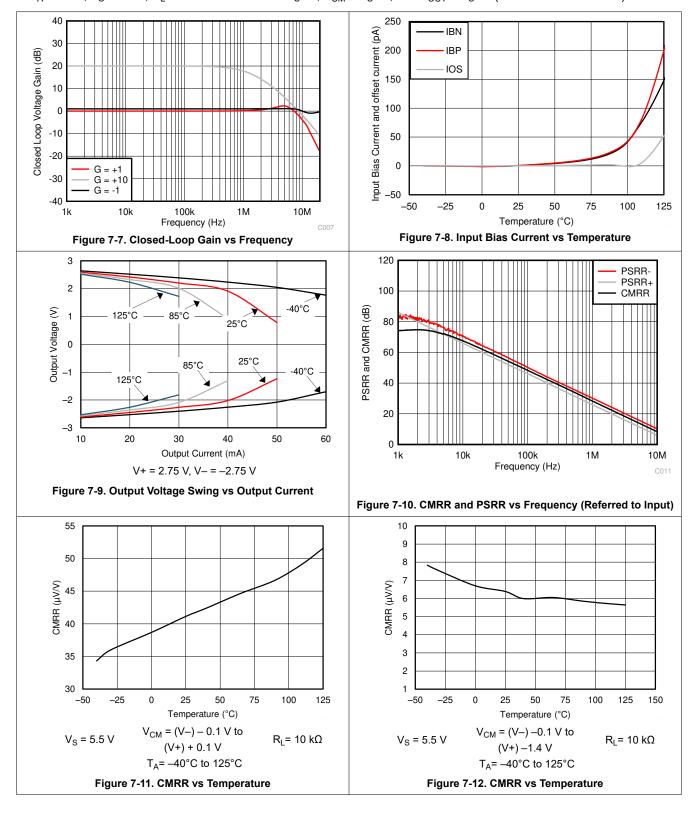
7.8 Typical Characteristics

at $T_A = 25$ °C, $V_S = 5.5$ V, $R_L = 10$ k Ω connected to $V_S / 2$, $V_{CM} = V_S / 2$, and $V_{OUT} = V_S / 2$ (unless otherwise noted)





at T_A = 25°C, V_S = 5.5 V, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)





at T_A = 25°C, V_S = 5.5 V, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)

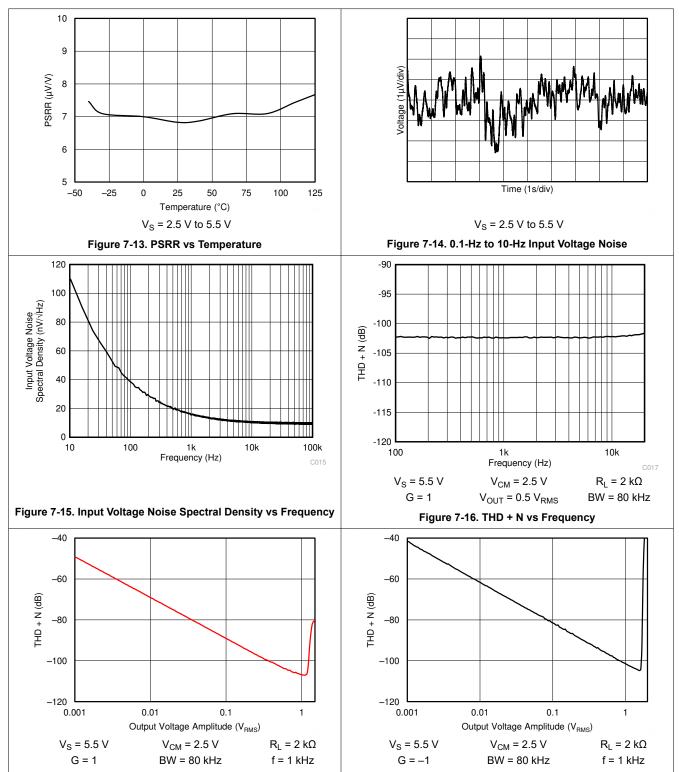
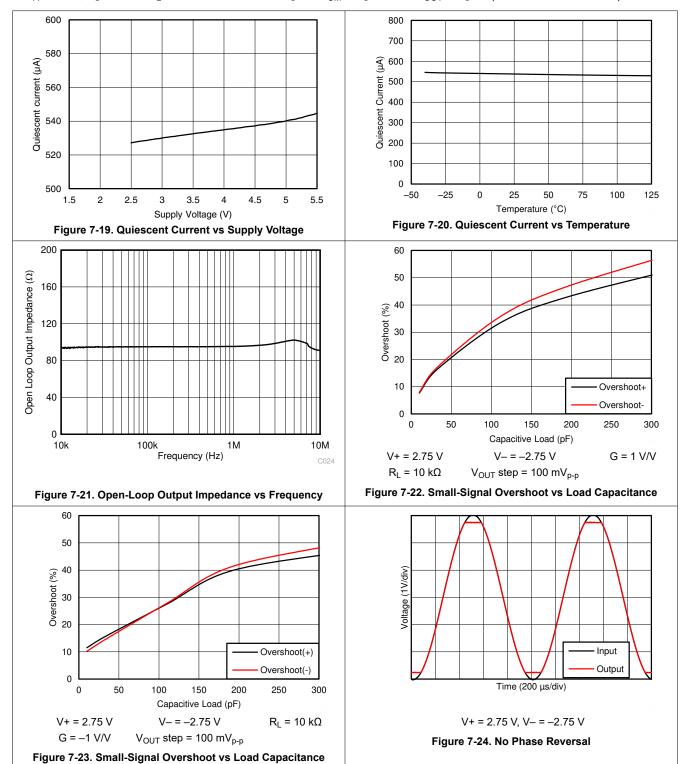


Figure 7-17. THD + N vs Amplitude

Figure 7-18. THD + N vs Amplitude

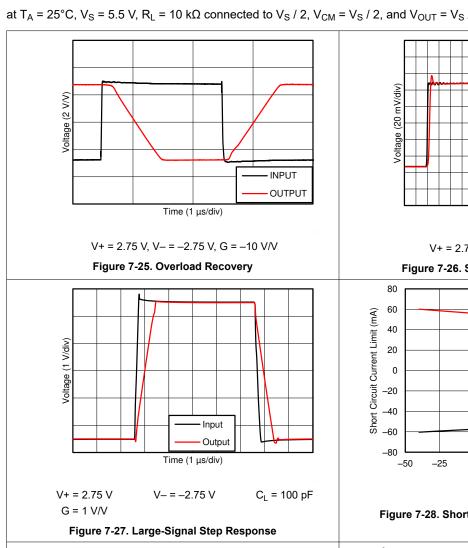


at T_A = 25°C, V_S = 5.5 V, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)





at $T_A = 25$ °C, $V_S = 5.5$ V, $R_L = 10$ k Ω connected to $V_S / 2$, $V_{CM} = V_S / 2$, and $V_{OUT} = V_S / 2$ (unless otherwise noted)



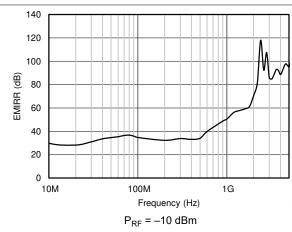
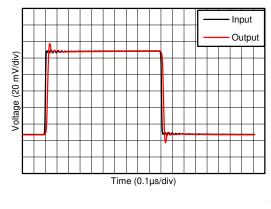


Figure 7-29. Electromagnetic Interference Rejection Ratio Referred to Noninverting Input (EMIRR+) vs Frequency



V+ = 2.75 V, V- = -2.75 V, G = 1 V/V

Figure 7-26. Small-Signal Step Response

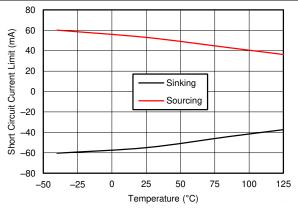


Figure 7-28. Short-Circuit Current vs Temperature

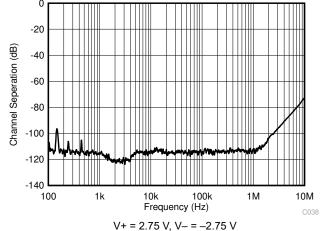
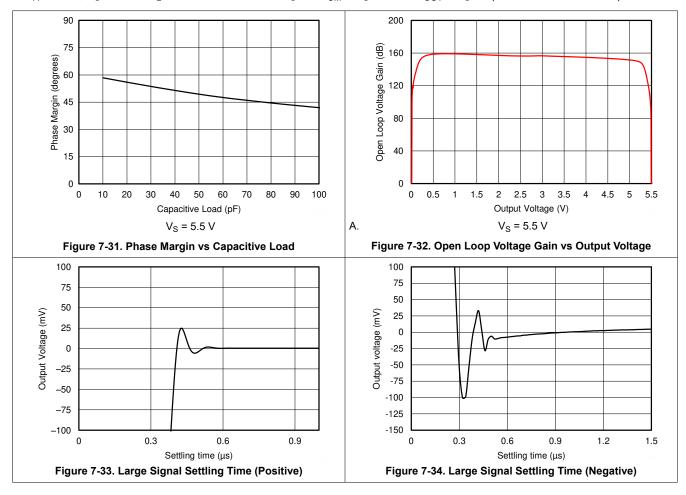


Figure 7-30. Channel Separation vs Frequency



at $T_A = 25$ °C, $V_S = 5.5$ V, $R_L = 10$ k Ω connected to $V_S / 2$, $V_{CM} = V_S / 2$, and $V_{OUT} = V_S / 2$ (unless otherwise noted)



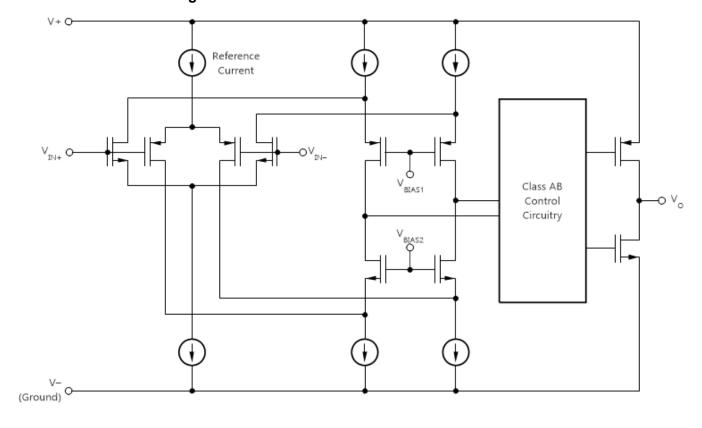


8 Detailed Description

8.1 Overview

The TSV91xA-Q1 series is a family of low-power, rail-to-rail input and output op amps. These devices operate from 2.5 V to 5.5 V, are unity-gain stable, and are designed for a wide range of general-purpose automotive applications. The input common-mode voltage range includes both rails and allows the TSV91xA-Q1 series to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications and are designed for driving sampling analog-to-digital converters (ADCs).

8.2 Functional Block Diagram





8.3 Feature Description

8.3.1 Rail-to-Rail Input

The input common-mode voltage range of the TSV91xA-Q1 family extends 100 mV beyond the supply rails for the full supply voltage range of 2.5 V to 5.5 V. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in the *Functional Block Diagram*. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.4 V to 100 mV above the positive supply, whereas the P-channel pair is active for inputs from 100 mV below the negative supply to approximately (V+) - 1.4 V. There is a small transition region, typically (V+) - 1.2 V to (V+) - 1 V, in which both pairs are on. This 200-mV transition region can vary up to 200 mV with process variation. Thus, the transition region (with both stages on) can range from (V+) - 1.4 V to (V+) - 1.2 V on the low end, and up to (V+) - 1 V to (V+) - 0.8 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can degrade compared to device operation outside this region.

8.3.2 Rail-to-Rail Output

Designed as a low-power, low-voltage operational amplifier, the TSV91xA-Q1 series delivers a robust output drive capability. A class AB output stage with common-source transistors achieves full rail-to-rail output swing capability. For resistive loads of 10 k Ω , the output swings to within 15 mV of either supply rail, regardless of the applied power-supply voltage. Different load conditions change the ability of the amplifier to swing close to the rails.

8.3.3 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the rated operating voltage, because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return to the linear state. After the charge carriers return to the linear state, the device begins to slew at the specified slew rate. Therefore, the propagation delay (in case of an overload condition) is the sum of the overload recovery time and the slew time. The overload recovery time for the TSV91xA-Q1 series is approximately 200 ns.

8.4 Device Functional Modes

The TSV91xA-Q1 family has a single functional mode. These devices are powered on as long as the power-supply voltage is between 2.5 V (±1.25 V) and 5.5 V (±2.75 V).

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The TSV91xA-Q1 series features 8-MHz bandwidth and 4.5-V/ μ s slew rate with only 550 μ A of supply current per channel, providing good AC performance at low power consumption. DC applications are well served with a low input noise voltage of 18 nV / $\sqrt{\text{Hz}}$ at 1 kHz, low input bias current, and a typical input offset voltage of 0.3 mV.

9.2 Typical Application

Figure 9-1 shows the TSV91xA-Q1 configured in a low-side, motor-control application.

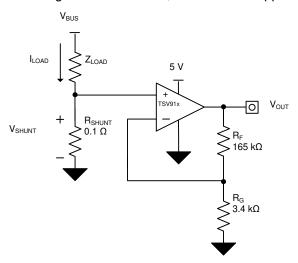


Figure 9-1. TSV91xA-Q1 in a Low-Side, Motor-Control Application

9.2.1 Design Requirements

The design requirements for this design are as follows:

Load current: 0 A to 1 AOutput voltage: 4.95 V

Maximum shunt voltage: 100 mV



9.2.2 Detailed Design Procedure

The transfer function of the circuit in Figure 9-1 is shown in Equation 1.

$$V_{OUT} = I_{LOAD} \times R_{SHUNT} \times Gain$$
 (1)

The load current (I_{LOAD}) produces a voltage drop across the shunt resistor (R_{SHUNT}). The load current is set from 0 A to 1 A. To keep the shunt voltage below 100 mV at maximum load current, the largest shunt resistor is defined using Equation 2.

$$R_{SHUNT} = \frac{V_{SHUNT_MAX}}{I_{LOAD_MAX}} = \frac{100 \text{ mV}}{1 \text{ A}} = 100 \text{ m}\Omega$$
 (2)

Using Equation 2, R_{SHUNT} is 100 m Ω . The voltage drop produced by I_{LOAD} and R_{SHUNT} is amplified by the TSV91xA-Q1 to produce an output voltage of approximately 0 V to 4.95 V. The gain required by the TSV91xA-Q1 to produce the necessary output voltage is calculated using Equation 3:

$$Gain = \frac{(V_{OUT_MAX} - V_{OUT_MIN})}{(V_{IN\ MAX} - V_{IN\ MIN})}$$
(3)

Using Equation 3, the required gain is calculated to be 49.5 V/V, which is set with resistors R_F and R_G . Equation 4 is used to size the resistors, R_F and R_G , to set the gain of the TSV91xA-Q1 to 49.5 V/V.

$$Gain = 1 + \left(\frac{R_F}{R_G}\right) \tag{4}$$

Selecting R_F as 165 $k\Omega$ and R_G as 3.4 $k\Omega$ provides a combination that equals roughly 49.5 V/V. Figure 9-2 shows the measured transfer function of the circuit shown in Figure 9-1.

9.2.3 Application Curve

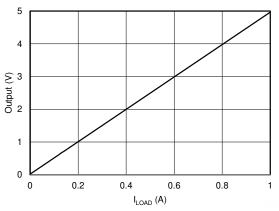


Figure 9-2. Low-Side, Current-Sense, Transfer Function

9.3 Power Supply Recommendations

The TSV91xA-Q1 series is specified for operation from 2.5 V to 5.5 V (±1.25 V to ±2.75 V); many specifications apply from –40°C to 125°C. *Typical Characteristics* presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

CAUTION

Supply voltages larger than 6 V can permanently damage the device; see the *Absolute Maximum Ratings* table.

Place 0.1-µF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see *Layout Example*.

9.3.1 Input and ESD Protection

The TSV91xA-Q1 series incorporates internal ESD protection circuits on all pins. For input and output pins, this protection consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10-mA, as stated in the *Absolute Maximum Ratings* table. Figure 9-3 shows how a series input resistor is added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and the value must be kept to a minimum in noise-sensitive applications.

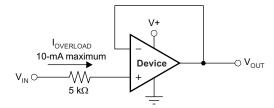


Figure 9-3. Input Current Protection

9.4 Layout

9.4.1 Layout Guidelines

For best operational performance of the device, use good printed-circuit board (PCB) layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and of op amp itself. Bypass capacitors are used to reduce the coupled noise by providing low-impedance power sources local to the analog circuitry.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of circuitry is one of the simplest and most-effective methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground planes. A ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise pickup. Make sure to physically separate digital and analog grounds, paying attention to the flow of the ground current.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicular is much better as opposed to in parallel with the noisy trace.
- Place the external components as close to the device as possible. As shown in Figure 9-5, keeping RF and RG close to the inverting input minimizes parasitic capacitance on the inverting input.
- Keep the length of input traces as short as possible. Always remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.
- Cleaning the PCB following board assembly is recommended for best performance.
- Any precision integrated circuit can experience performance shifts resulting from moisture ingress into the
 plastic package. Following any aqueous PCB cleaning process, baking the PCB assembly is recommended
 to remove moisture introduced into the device packaging during the cleaning process. A low-temperature,
 post-cleaning bake at 85°C for 30 minutes is sufficient for most circumstances.



9.4.2 Layout Example

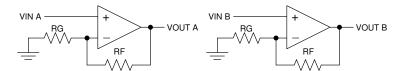


Figure 9-4. Schematic Representation of Layout Example

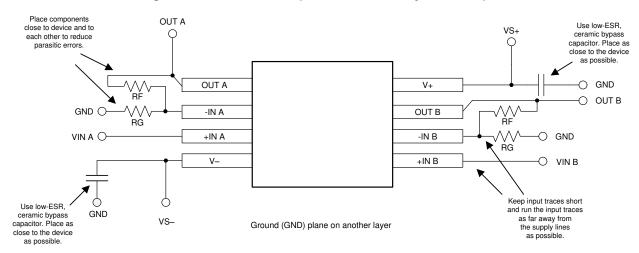


Figure 9-5. Layout Example

10 Device and Documentation Support

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking
	(1)	(2)			(3)	(4)	(5)		(6)
TSV911AQDBVRQ1	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	1N4
TSV911AQDBVRQ1.A	Active	Production	SOT-23 (DBV) 5	3000 LARGE T&R	Yes	SN	Level-1-260C-UNLIM	-40 to 125	1N4
TSV911AQDCKRQ1	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1N6
TSV911AQDCKRQ1.A	Active	Production	SC70 (DCK) 5	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1N6
TSV912AQDGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	29IT
TSV912AQDGKRQ1.A	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	29IT
TSV912AQDRQ1	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TS912Q
TSV912AQDRQ1.A	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TS912Q
TSV912AQPWRQ1	Active	Production	TSSOP (PW) 8	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TSV912
TSV912AQPWRQ1.A	Active	Production	TSSOP (PW) 8	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TSV912
TSV914AQDRQ1	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TSV914AQD
TSV914AQDRQ1.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TSV914AQD
TSV914AQPWRQ1	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	T914AQ
TSV914AQPWRQ1.A	Active	Production	TSSOP (PW) 14	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	T914AQ

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



PACKAGE OPTION ADDENDUM

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Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

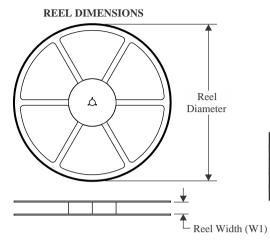
Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

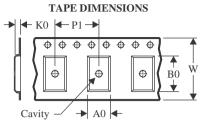
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.



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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

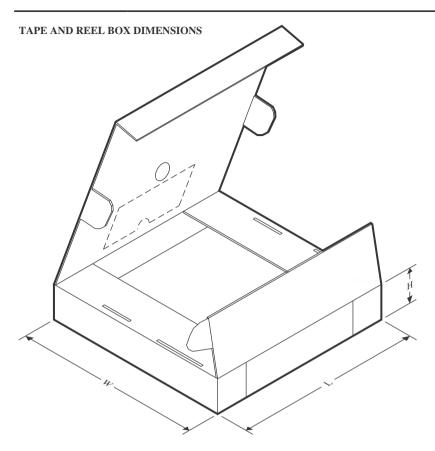


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TSV911AQDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TSV911AQDCKRQ1	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TSV912AQDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.25	3.35	1.25	8.0	12.0	Q1
TSV912AQDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TSV912AQDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TSV912AQPWRQ1	TSSOP	PW	8	3000	330.0	12.4	7.0	3.6	1.6	8.0	12.0	Q1
TSV914AQDRQ1	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
TSV914AQPWRQ1	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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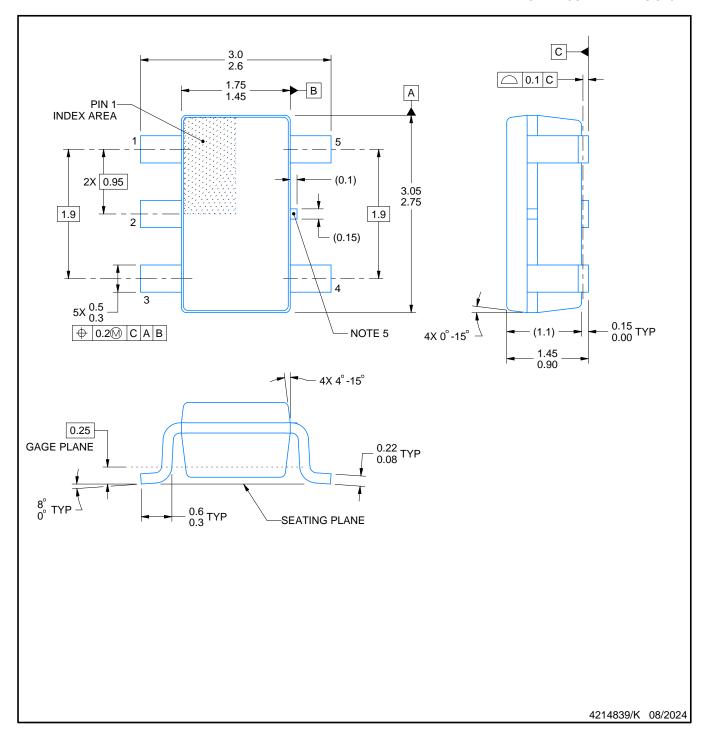


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TSV911AQDBVRQ1	SOT-23	DBV	5	3000	210.0	185.0	35.0
TSV911AQDCKRQ1	SC70	DCK	5	3000	190.0	190.0	30.0
TSV912AQDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
TSV912AQDGKRQ1	VSSOP	DGK	8	2500	353.0	353.0	32.0
TSV912AQDRQ1	SOIC	D	8	2500	353.0	353.0	32.0
TSV912AQPWRQ1	TSSOP	PW	8	3000	353.0	353.0	32.0
TSV914AQDRQ1	SOIC	D	14	2500	353.0	353.0	32.0
TSV914AQPWRQ1	TSSOP	PW	14	2000	353.0	353.0	32.0



SMALL OUTLINE TRANSISTOR



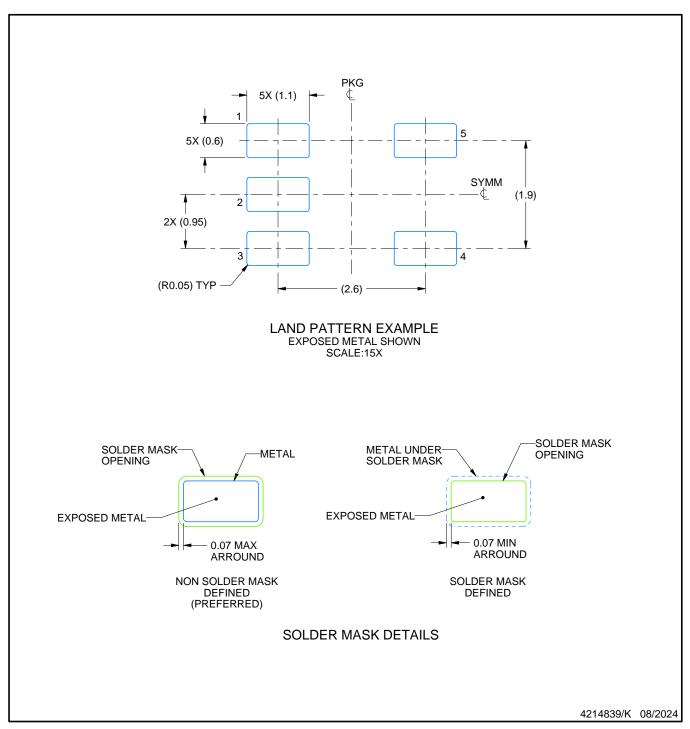
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Reference JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- 5. Support pin may differ or may not be present.



SMALL OUTLINE TRANSISTOR



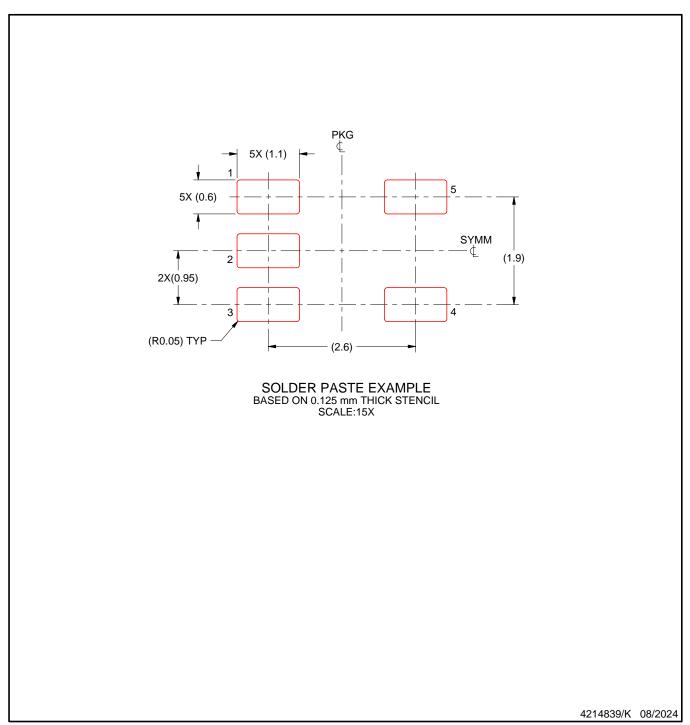
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



NOTES:

PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.



SMALL OUTLINE PACKAGE



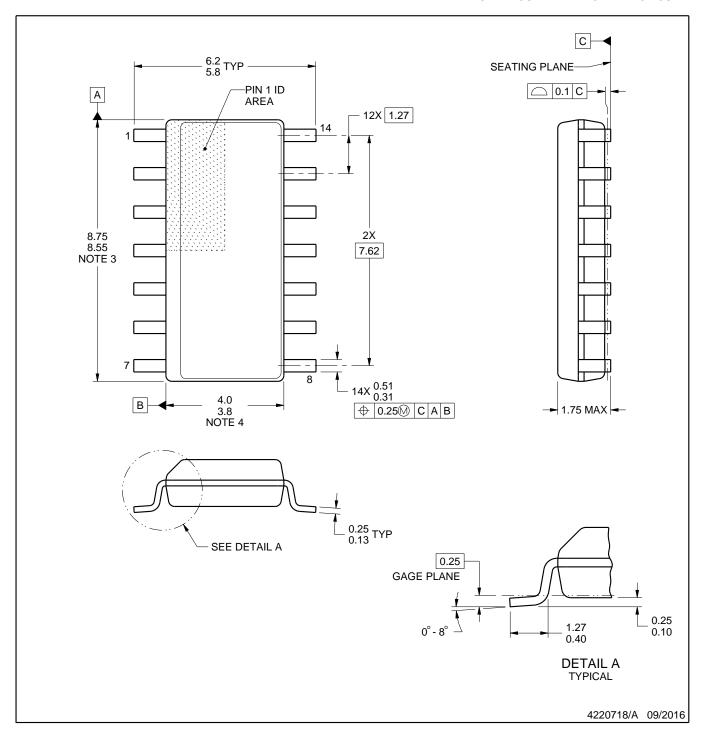
NOTES: (continued)

- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

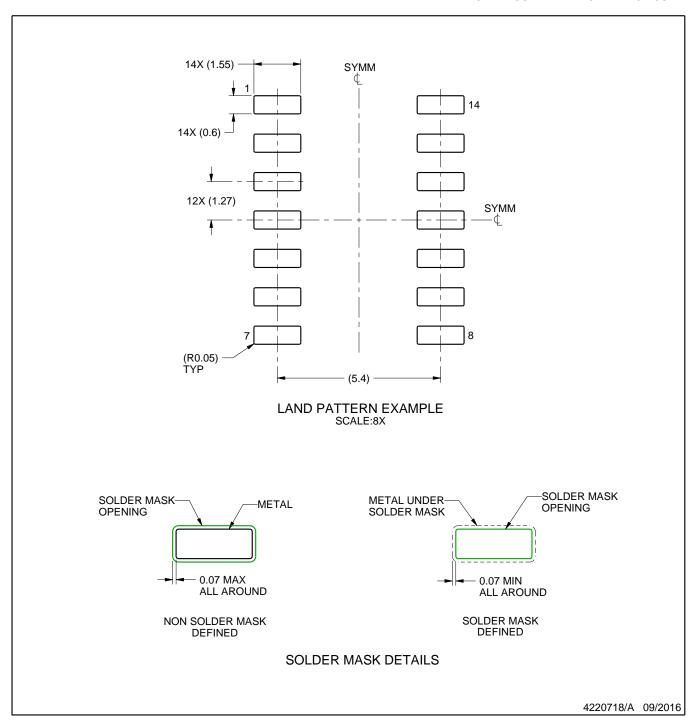
- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



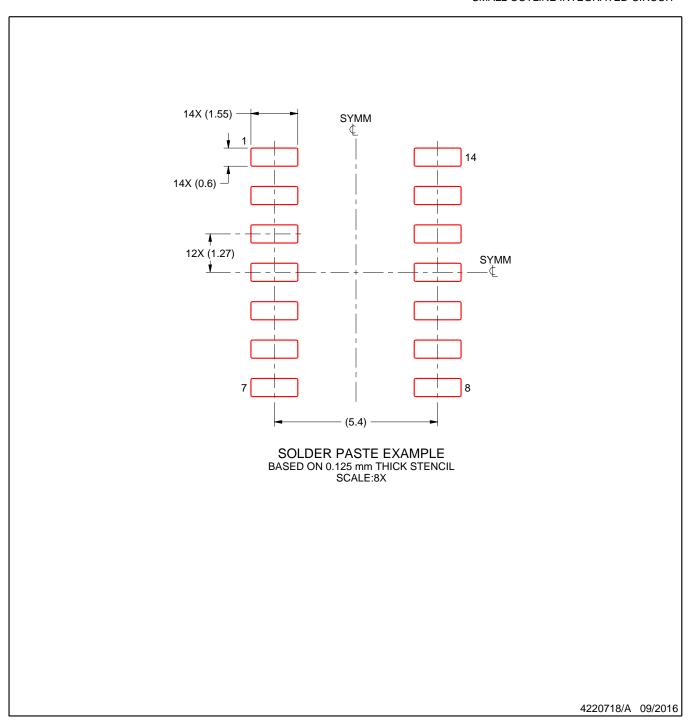
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



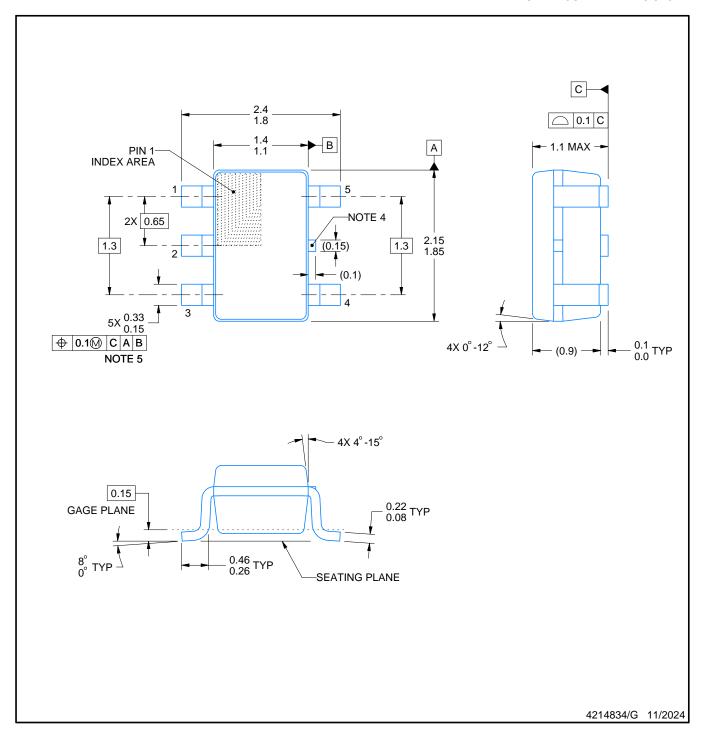
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE TRANSISTOR

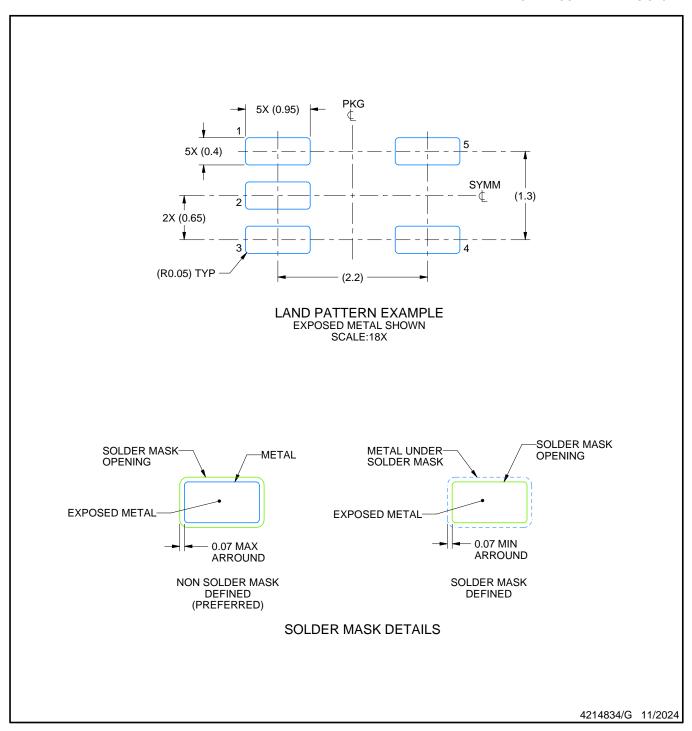


- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Reference JEDEC MO-203.

- 4. Support pin may differ or may not be present.5. Lead width does not comply with JEDEC.
- 6. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25mm per side



SMALL OUTLINE TRANSISTOR

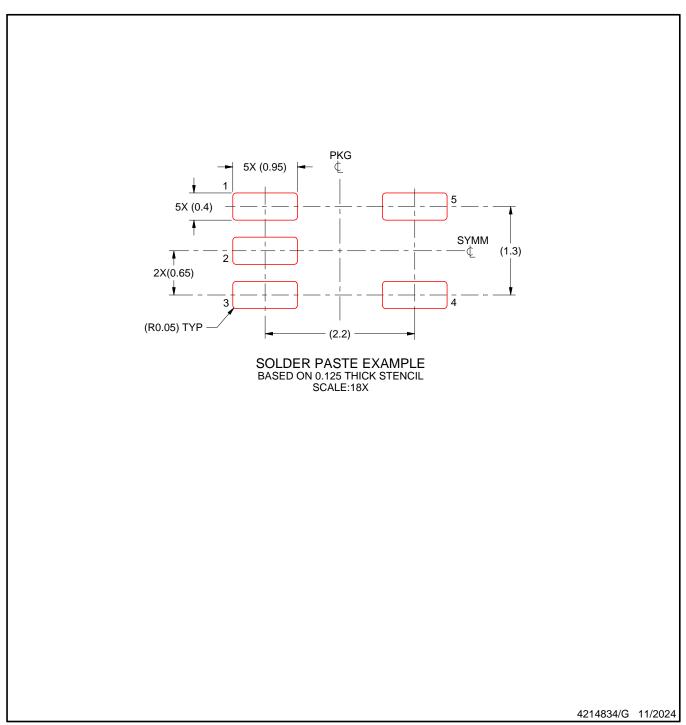


NOTES: (continued)

7. Publication IPC-7351 may have alternate designs.8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR

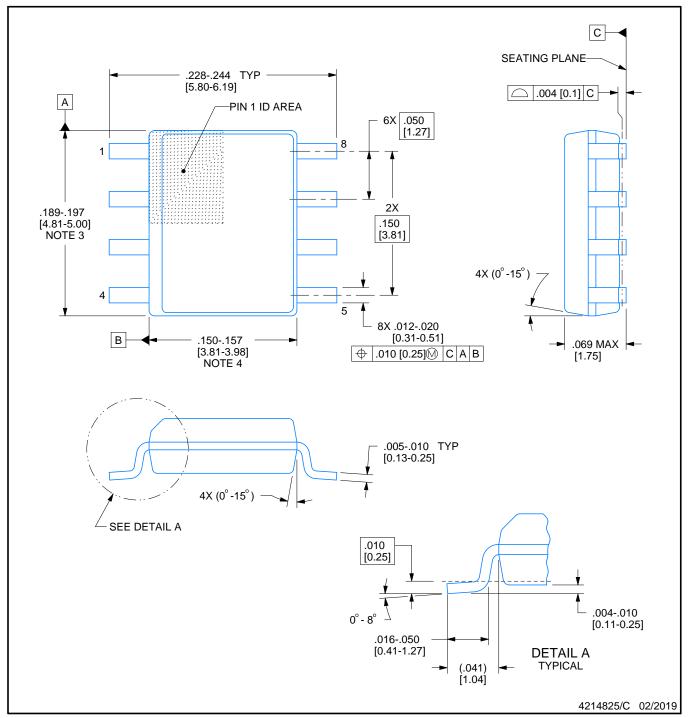


- 9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 10. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE INTEGRATED CIRCUIT



- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



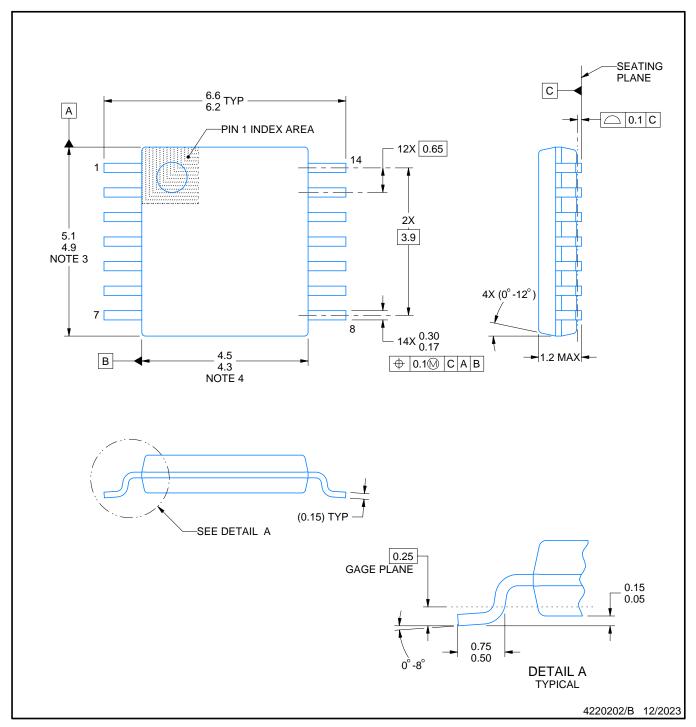
SMALL OUTLINE INTEGRATED CIRCUIT



- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





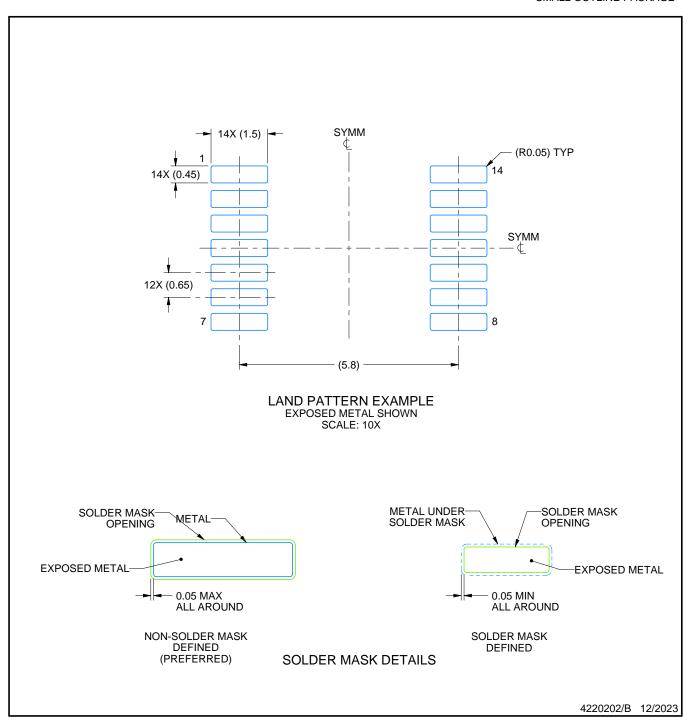


- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



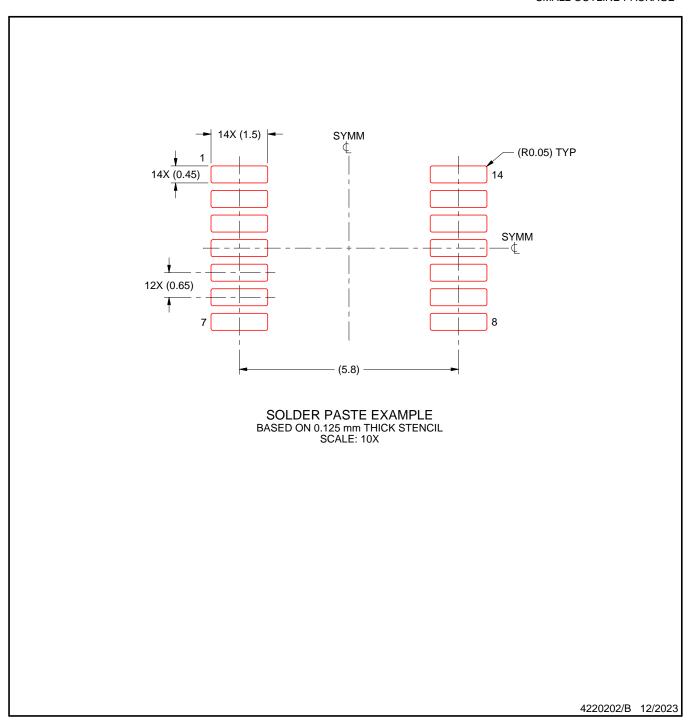


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

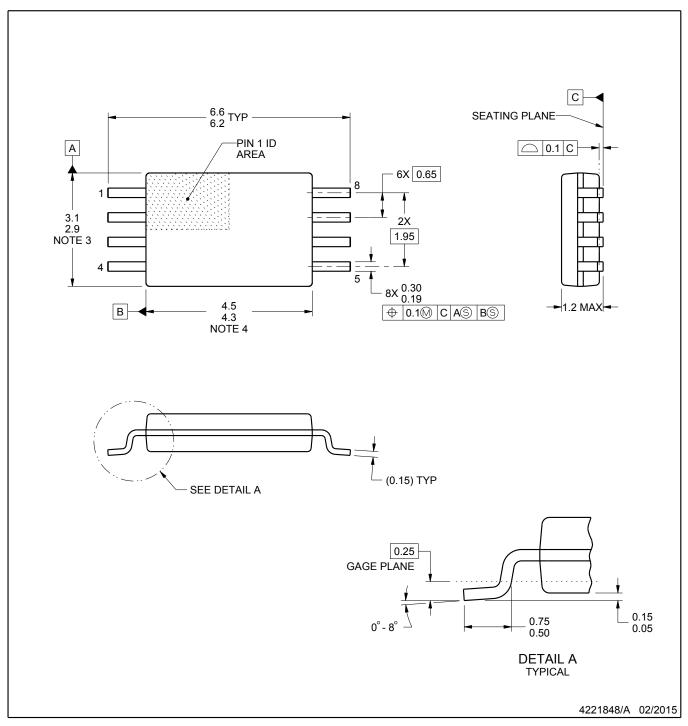




- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





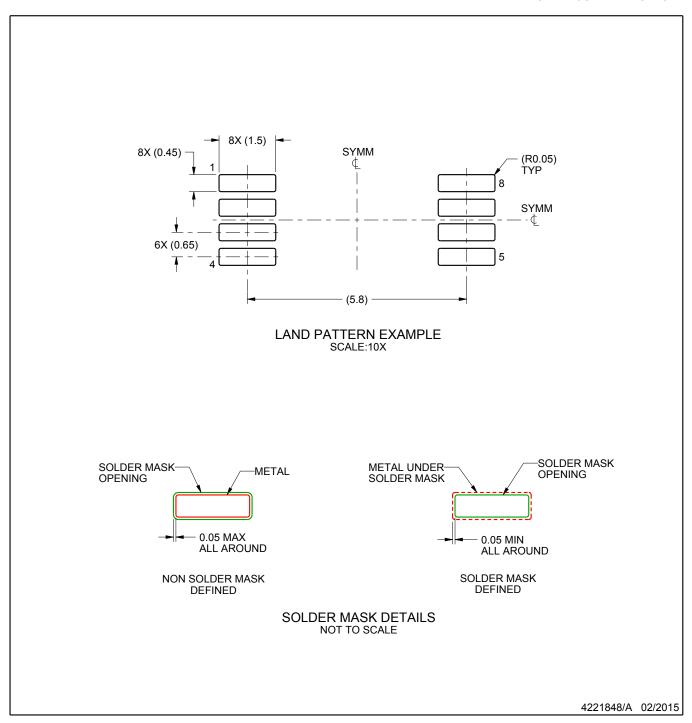


- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153, variation AA.



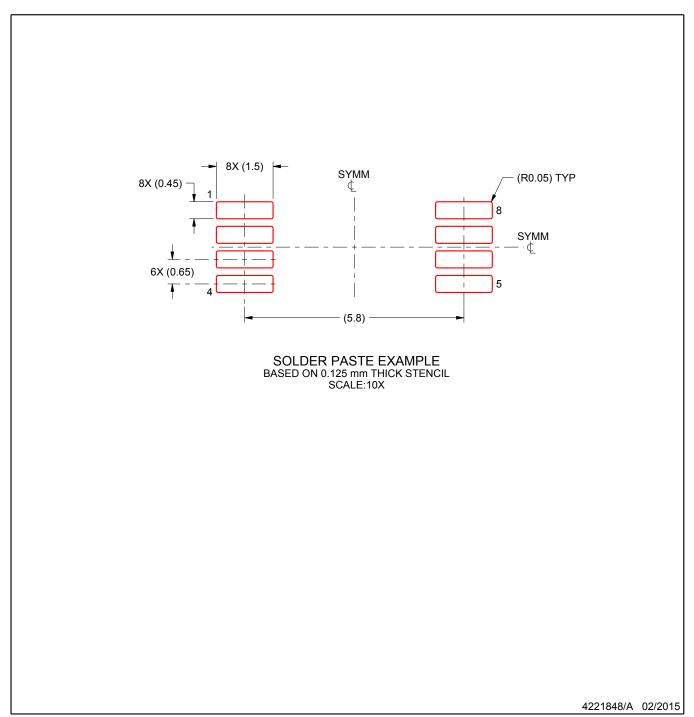


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





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Last updated 10/2025